

PRODUCT/PROCESS CHANGE NOTIFICATION

PCN APM-LOG/08/3402 Notification Date 01/30/2008

NEW SITE FOR ELECTRONIC WAFER SORT WITH TEST PLATFORM CHANGE

LOG - ADV ANALOG/LOGIC

Table 1. Change Implementation Schedule

- date in a number of the state		
Forecasted implementation date for change	15-Apr-2008	
Forecasted availability date of samples for customer	01-Apr-2008	
Forecasted date for STMicroelectronics change Qualification Plan results availability	01-Apr-2008	
Estimated date of changed product first shipment	15-Apr-2008	

Table 2. Change Identification

Product Identification (Product Family/Commercial Product)	See attached	
Type of change	Multiple types of changes	
Reason for change	EWS test site and test platform change	
Description of the change	The Advanced Analog division of STMicroelectronics is transitioning Electronic Wafer Sort (EWS) to ST's site in Singapore. The spectrum of affected products includes NVRAMs, supervisors and serial real-time clocks. This transition requires moving to newer test platforms. The affected part numbers are listed on page 6. The test coverage and test flows will remain the same. This change will be transparent to users.	
Product Line(s) and/or Part Number(s)	See attached	
Description of the Qualification Plan	See attached	
Change Product Identification	See attached	
Manufacturing Location(s)		

Table 3. List of Attachments	
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Customer Part numbers list	
Qualification Plan results	

Customer Acknowledgement of Receipt	PCN APM-LOG/08/3402
Please sign and return to STMicroelectronics Sales Office	Notification Date 01/30/2008
□ Qualification Plan Denied	Name:
□ Qualification Plan Approved	Title:
	Company:
□ Change Denied	Date:
□ Change Approved	Signature:
Remark	
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DOCUMENT APPROVAL

Name	Function	
Mcdonagh, Gary Division Marketing Manager		
Sonnino, Ruben	Division Product Manager	
Winn, Robert E	Division Q.A. Manager	

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The Advanced Analog division of STMicroelectronics is transitioning Electronic Wafer Sort (EWS) to ST's site in Singapore. The spectrum of affected products includes NVRAMs, supervisors and serial real-time clocks.

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WHY?

The Carrollton EWS site is being relocated to Singapore.

WHEN?

Devices coming through the new EWS site could begin shipping as soon as April 15, 2008. Samples will be available on request.

HOW WILL THE CHANGE BE QUALIFIED?

Qualification is being done according to STMicroelectronics Corporate procedure. The first qualification reports will be available by April 1, 2008, upon request.

IMPACT ESTIMATION AT USER'S SIDE

The new EWS test site and test platform changes will not impact users.

ABOUT TRACEABILITY

All devices are marked with a trace code which provides for tracking. With this information, it is possible to determine the exact flow of any device including the EWS site.

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Affected devices:

M40SZ100WMQ6E	M41ST87WMX6TR	M48T18-100PC1	M48Z02-150PC1
M40SZ100WMQ6F	M41ST95WMX6TR	M48T18-150PC1	M48Z02-200PC1
M40Z300VMQ6TR	M41ST85WMX6TR	M48T201V-85MH1E	M48Z02-70PC1
M40Z300WMQ6E	M41ST87YMX6TR	M48T201V-85MH1F	M48Z08-100PC1
M40Z300WMQ6F	M41T0M6E	M48T201Y-70MH1E	M48Z12-150PC1
M40Z111MH6E	M41T0M6F	M48T201Y-70MH1F	M48Z12-200PC1
M40Z111MH6F	M41T80M6E	M48T212V-85MH1E	M48Z12-70PC1
M40Z111WMH6E	M41T80M6F	M48T212V-85MH1F	M48Z18-100PC1
M40Z111WMH6F	M41T94MQ6E	M48T35-70PC1	M48Z32V-35MT1E
M40Z300WMH6E	M41T94MQ6F	M48T35AV-10PC1	M48Z32V-35MT1F
M40Z300WMH6F	M41T94MH6E	M48T35Y-70PC1	M48Z35-70PC1
M40Z300AVMQ6F	M41T94MH6F	M48T35Y-70MH1E	M48Z35AV-10PC1
M40Z300AVMQ6E	M48T02-150PC1	M48T35Y-70MH1F	M48Z35Y-70PC1
M41ST85WMH6E	M48T02-200PC1	M48T35AV-10MH1E	M48Z35AV-10MH1E
M41ST85WMH6F	M48T02-70PC1	M48T35AV-10MH1F	M48Z35Y-70MH1E
M41ST87WMX6	M48T08-100PC1	M48T37Y-70MH1E	M48Z35Y-70MH1F
M41ST85WMX6	M48T08-150PC1	M48T37Y-70MH1F	M48Z58-70PC1
M41ST95WMX6	M48T08Y-10MH1E	M48T37V-10MH1E	M48Z58Y-70PC1
M41ST87YMX6	M48T08Y-10MH1F	M48T37V-10MH1F	M48Z58Y-70MH1F
M41ST84WMQ6E	M48T12-150PC1	M48T58Y-70MH1E	M48Z58Y-70MH1E
M41ST84WMQ6F	M48T12-70PC1	M48T58Y-70MH1F	
	_	M48T58Y-70PC1	
		M48T58-70PC1	

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